

# N-channel TrenchMOS standard level FET Rev. 03 — 1 February 2011

Product data sheet

#### **Product profile** 1.

### 1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

### 1.2 Features and benefits

- AEC Q101 compliant
- Low conduction losses due to low on-state resistance
- **1.3 Applications** 
  - 12 V and 24 V loads
  - Automotive and general purpose power switching

### 1.4 Quick reference data

#### Table 1 Quick reference data

Table 1.	Quick relefence	uala					
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{\text{DS}}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	55	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	[1]	-	-	75	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	-	300	W
Static cha	aracteristics						
R <sub>DSon</sub>	drain-source on-state resistance	$\label{eq:VGS} \begin{array}{l} V_{GS} = 10 \text{ V}; \text{ I}_{D} = 25 \text{ A}; \\ T_{j} = 175 \ ^{\circ}\text{C}; \text{ see } \underline{\text{Figure 12}}; \\ \text{see } \underline{\text{Figure 13}} \end{array}$		-	-	13.2	mΩ
		$V_{GS}$ = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>		-	5.3	6.3	mΩ



Motors, lamps and solenoids

sources

Suitable for standard level gate drive

Suitable for thermally demanding environments due to 175 °C rating

# BUK7606-55A

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanche	e ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 75 \text{ A};  V_{\text{sup}} \leq 55 \text{ V}; \\ R_{\text{GS}} &= 50  \Omega;  V_{\text{GS}} = 10 \text{ V}; \\ T_{j(\text{init})} &= 25 ^{\circ}\text{C}; \text{ unclamped} \end{split} $	-	-	1.1	J

[1] Continuous current is limited by package.

### 2. Pinning information

Table 2.	Pinning	j information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	drain	mb	D
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S
			SOT404 (D2PAK)	

### 3. Ordering information

Table 3. Orderin	ig information		
Type number	Package		
	Name	Description	Version
BUK7606-55A	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404

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### 4. Limiting values

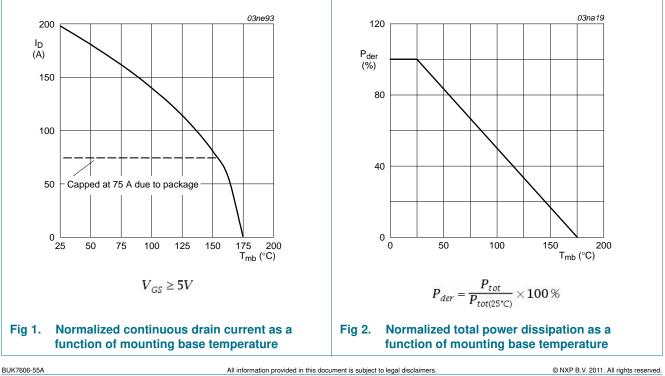
#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
Symbol				IVIIII		
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	55	V
$V_{DGR}$	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	55	V
V <sub>GS</sub>	gate-source voltage			-20	20	V
I <sub>D</sub>	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure 1}}{\text{Figure 1}};$	<u>[1]</u>	-	154	А
		see <u>Figure 3</u>	[2]	-	75	А
		$T_{mb}$ = 100 °C; $V_{GS}$ = 10 V; see Figure 1	[2]	-	75	А
I <sub>DM</sub>	peak drain current	$T_{mb}$ = 25 °C; pulsed; $t_p \le 10 \ \mu$ s; see <u>Figure 3</u>		-	616	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	300	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-drain	1 diode					
ls	source current	T <sub>mb</sub> = 25 °C	[1]	-	154	А
			[2]	-	75	А
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$		-	616	А
Avalanche ru	uggedness					
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	I <sub>D</sub> = 75 A; V <sub>sup</sub> ≤ 55 V; R <sub>GS</sub> = 50 Ω; V <sub>GS</sub> = 10 V; T <sub>j(init)</sub> = 25 °C; unclamped		-	1.1	J

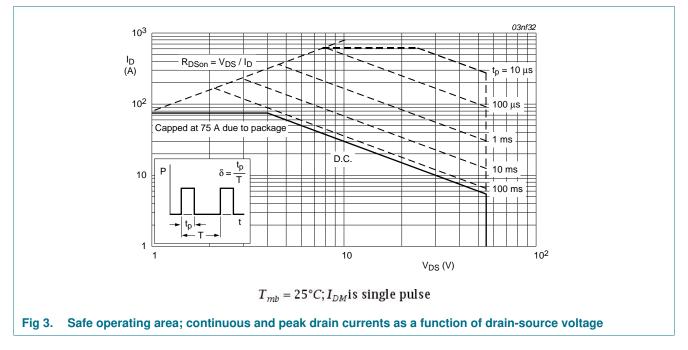
[1] Current is limited by power dissipation chip rating.

[2] Continuous current is limited by package.



# BUK7606-55A

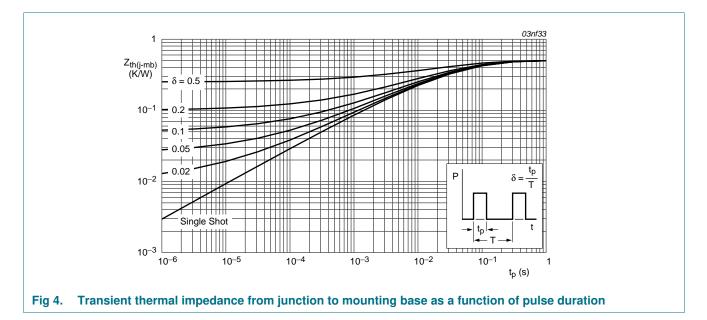
### N-channel TrenchMOS standard level FET



### 5. Thermal characteristics

#### Table 5.Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 4	-	-	0.5	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	mounted on printed-circuit board; minimum footprint	-	50	-	K/W



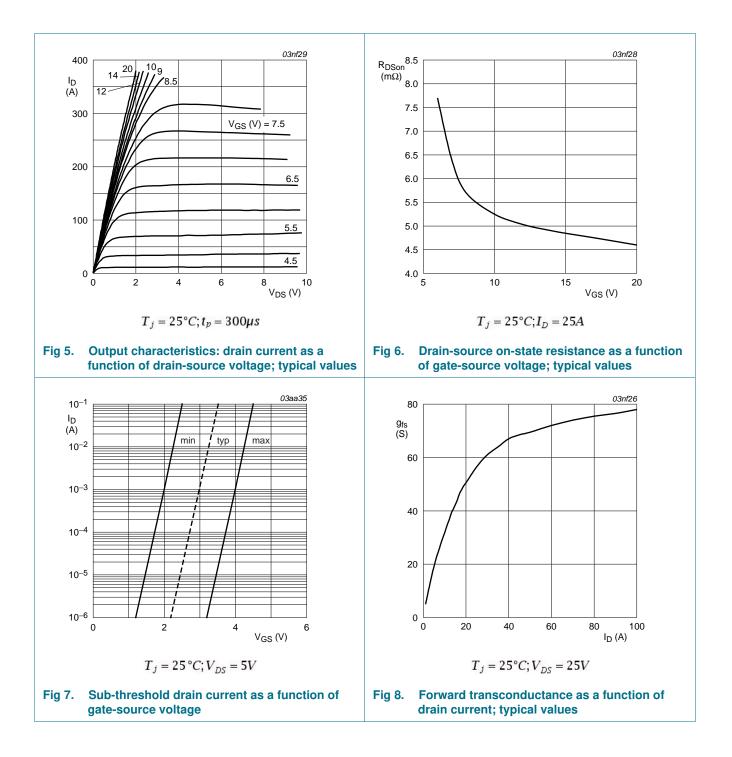
### N-channel TrenchMOS standard level FET

#### **Characteristics** 6.

Static characteristics         Ip = 0.25 mA; V <sub>0S</sub> = 0 V; T <sub>j</sub> = 25 °C         55         .         .         V           V <sub>(BR)DSS</sub> drain-source breakdown voltage         Ip = 0.25 mA; V <sub>0S</sub> = 0 V; T <sub>j</sub> = .55 °C         50         .         .         V           V <sub>0S(th)</sub> gate-source threshold voltage         Ip = 1 mA; V <sub>DS</sub> = V <sub>OS</sub> ; T <sub>j</sub> = .55 °C;         .         .         .         .         .         V           Ip = 1 mA; V <sub>DS</sub> = V <sub>OS</sub> ; T <sub>j</sub> = .55 °C;         . </th <th>Table 6.</th> <th>Characteristics</th> <th></th> <th></th> <th></th> <th></th> <th></th>	Table 6.	Characteristics					
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	Static cha	aracteristics					
$V_{GS(th)} \begin{tabular}{ c                                   $	V <sub>(BR)DSS</sub>		$I_D = 0.25 \text{ mA};  V_{GS} = 0  \text{V};  \text{T}_j = 25 ^\circ\text{C}$	55	-	-	V
		breakdown voltage	$I_D$ = 0.25 mA; $V_{GS}$ = 0 V; $T_j$ = -55 °C	50	-	-	V
			,	2	3	4	V
$\begin{array}{c c c c c c c c c c c c c c c c c c c $				1	-	-	V
$ \frac{V_{DS} = 55 \text{ V; } \text{V}_{GS} = 0 \text{ V; } \text{T}_{\text{J}} = 25 ^{\circ}\text{C} - 0.05 10 \mu\text{A} \\ V_{GS} = 20 \text{ V; } V_{DS} = 0 \text{ V; } \text{T}_{\text{J}} = 25 ^{\circ}\text{C} - 2 100 \text{ nA} \\ V_{GS} = -20 \text{ V; } V_{DS} = 0 \text{ V; } \text{T}_{\text{J}} = 25 ^{\circ}\text{C} - 2 100 \text{ nA} \\ V_{GS} = -20 \text{ V; } V_{DS} = 0 \text{ V; } \text{T}_{\text{J}} = 25 ^{\circ}\text{C} - 2 100 \text{ nA} \\ V_{GS} = -20 \text{ V; } V_{DS} = 0 \text{ V; } \text{T}_{\text{J}} = 25 ^{\circ}\text{C} - 2 100 \text{ nA} \\ V_{GS} = 10 \text{ V; } \text{I}_{D} = 25 \text{ A; } \text{T}_{\text{J}} = 175 ^{\circ}\text{C}; \\ see \text{ Figure 12; see Figure 13} \\ \hline V_{GS} = 10 \text{ V; } \text{I}_{D} = 25 \text{ A; } \text{T}_{\text{J}} = 25 ^{\circ}\text{C}; \\ see \text{ Figure 12; see Figure 13} \\ \hline \text{Dynamic characteristics} \\ \hline \text{Dynamic characteristics} \\ \hline \text{C}_{\text{css}} & \text{input capacitance} \\ \text{reverse transfer} \\ \text{capacitance} \\ \hline \text{T}_{\text{J}} = 25 ^{\circ}\text{C}; \text{ see Figure 14} \\ \hline \text{C}_{\text{rss}} & \text{reverse transfer} \\ \text{capacitance} \\ \hline \text{T}_{\text{J}} = 25 ^{\circ}\text{C}; \text{ see Figure 14} \\ \hline \text{C}_{\text{rss}} & \text{reverse transfer} \\ \text{capacitance} \\ \hline \text{turn-on delay time} \\ \text{tr} & \text{rise time} \\ \hline \text{C}_{\text{rss}} & \text{reverse transfer} \\ \text{capacitance} \\ \hline \text{T}_{\text{J}} = 25 ^{\circ}\text{C} \\ \text{rese transfer} \\ \text{capacitance} \\ \hline \text{C}_{\text{rss}} & \text{internal drain} \\ \text{internal drain} \\ \text{internal drain} \\ \text{inductance} \\ \hline \text{form drain lead 6 mm from package to} \\ \text{centre of die ; T}_{\text{J}} = 25 ^{\circ}\text{C} \\ \hline \text{form upper edge of drain mounting base} \\ \text{to centre of die ; T}_{\text{J}} = 25 ^{\circ}\text{C} \\ \hline \text{form upper edge of drain mounting base} \\ \text{to centre of die ; T}_{\text{J}} = 25 ^{\circ}\text{C} \\ \hline \text{form upper edge of drain mounting base} \\ \text{to centre of die ; T}_{\text{J}} = 25 ^{\circ}\text{C} \\ \hline \text{form upper edge of drain mounting base} \\ \text{to centre of die ; T}_{\text{J}} = 25 ^{\circ}\text{C} \\ \hline \text{form upper edge of drain mounting base} \\ \text{to centre of die ; T}_{\text{J}} = 25 ^{\circ}\text{C} \\ \hline \text{form upper edge of drain mounting base} \\ \text{to centre of die ; T}_{\text{J}} = 25 ^{\circ}\text{C} \\ \hline \text{form upper edge of drain mounting base} \\ \text{to centre of die ; T}_{\text{J}} = 25 ^{\circ}\text{C} \\ \hline \text{form upper edge of drain mounting base} \\ to$			= = = ,	-	-	4.4	V
	I <sub>DSS</sub>	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μA
$ \begin{array}{ c c c c c } \hline V_{GS} = -20 \ V; \ V_{DS} = 0 \ V; \ T_{j} = 25 \ ^{\circ} C & - & 2 & 100 & nA \\ \hline R_{DSon} & drain-source on-state resistance & V_{GS} = 10 \ V; \ I_{D} = 25 \ A; \ T_{j} = 175 \ ^{\circ} C; \\ see \ Figure 12; see \ Figure 13 & V_{GS} = 10 \ V; \ I_{D} = 25 \ ^{\circ} C; \\ see \ Figure 12; see \ Figure 13 & V_{GS} = 10 \ V; \ V_{DS} = 25 \ ^{\circ} C; \\ see \ Figure 12; see \ Figure 13 & V_{GS} = 0 \ V; \ V_{DS} = 25 \ ^{\circ} C; \\ see \ Figure 12; see \ Figure 13 & V_{GS} = 0 \ V; \ V_{DS} = 25 \ ^{\circ} C; \\ see \ Figure 12; see \ Figure 13 & V_{GS} = 0 \ V; \ V_{DS} = 25 \ ^{\circ} C; \\ see \ Figure 12; see \ Figure 13 & V_{GS} = 0 \ V; \ V_{DS} = 25 \ ^{\circ} C; \\ see \ Figure 14 & 960 & 1200 \ PF \ C_{OSS} & output \ capacitance & T_{j} = 25 \ ^{\circ} C; see \ Figure 14 & 960 & 1200 \ PF \ C_{OSS} & reverse \ ransfer \ capacitance & V_{DS} = 30 \ V; \ T_{j} = 25 \ ^{\circ} C & 115 \ - & ns \ 110 \ PF \ C_{Sac} & 115 \ - & ns \ 110 \ - & ns \ 110$			$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μA
$ \begin{array}{cccccccccccccccccccccccccccccccccccc$	I <sub>GSS</sub>	gate leakage current	$V_{GS} = 20 \text{ V};  V_{DS} = 0 \text{ V};  T_{j} = 25 ^{\circ}\text{C}$	-	2	100	nA
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $			$V_{GS}$ = -20 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	2	100	nA
see Figure 12; see Figure 13Dynamic characteristics $C_{iss}$ input capacitance $V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$ $T_j = 25 °C; see Figure 14$ -45006000pF $C_{oss}$ output capacitance $T_j = 25 °C; see Figure 14$ -9601200pF $C_{rss}$ reverse transfer capacitance-510850pF $t_{d(on)}$ turn-on delay time $V_{DS} = 30 V; R_L = 1.2 \Omega; V_{GS} = 10 V;$ $R_G(ext) = 10 \Omega; T_j = 25 °C-35-nst_d(off)turn-off delay timeP_{G(ext)} = 10 \Omega; T_j = 25 °C-115-nst_d(off)turn-off delay timefrom drain lead 6 mm from package tocentre of die ; T_j = 25 °C-110-nsL_Dinternal draininductancefrom drain lead 6 mm from package tocentre of die ; T_j = 25 °C-2.5-nHL_Sinternal sourceinductancefrom source lead to source bond pad ;T_j = 25 °C-7.5-nHV_{SD}source-drain voltageI_S = 30 A; V_{GS} = 0 V; T_j = 25 °C;see Figure 15-0.851.2Vt_{rr}reverse recovery timeI_S = 20 A; d s/dt = -100 A/\mus;V_{rr} = 26 °C-800-ns$	R <sub>DSon</sub>			-	-	13.2	mΩ
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $				-	5.3	6.3	mΩ
$ \begin{array}{cccc} C_{oss} & output capacitance \\ C_{rss} & reverse transfer \\ capacitance \\ t_{d(on)} & turn-on delay time \\ t_{r} & rise time \\ t_{d(off)} & turn-off delay time \\ t_{f} & fall time \\ L_D & internal drain \\ inductance & \end{array}  \begin{array}{cccc} V_{DS} = 30 \ V; \ R_L = 1.2 \ \Omega; \ V_{GS} = 10 \ V; \\ F_T & rise time \\ T_T & fall time \\ L_D & internal drain \\ inductance & \end{array}  \begin{array}{cccc} rom drain lead 6 \ mm \ from \ package to \\ centre \ of \ die ; \ T_j = 25 \ ^{\circ}C \\ from \ upper edge \ of \ drain \ mounting \ base \\ to \ centre \ of \ die ; \ T_j = 25 \ ^{\circ}C \\ \end{array} \begin{array}{cccc} - & 115 & - & ns \\ - & 110 & - & ns \\ - & 0.85 & - & nH \\ - & 0.85 & 1.2 & V \\ - & se \\ \hline F_{trr} & reverse \ recovery \ time \\ - & Source-drain \ voltage \\ - & source \ l_S = 30 \ A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C \\ \hline V_{SD} & source-drain \ voltage \\ - & Source-drain \ voltage \\ - & Source \ drain \ V_{SD} \\ - & source \ drain \ V_{SD} \\ \hline V_{SD} & source-drain \ voltage \\ \hline V_{SD} & V_{SD} & source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \ voltage \\ \hline V_{SD} & V_{SD} & Source-drain \$	Dynamic	characteristics					
$\begin{array}{c c c c c c c c c c c c c c c c c c c $	C <sub>iss</sub>	input capacitance		-	4500	6000	pF
$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 14</u>	-	960	1200	pF
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	C <sub>rss</sub>			-	510	850	pF
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	t <sub>d(on)</sub>	turn-on delay time		-	35	-	ns
$\begin{array}{cccccccccccccccccccccccccccccccccccc$	t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \ \Omega; T_j = 25 \ ^{\circ}C$	-	115	-	ns
$ \begin{array}{c} L_{D} \\ L_{D} $	t <sub>d(off)</sub>	turn-off delay time		-	155	-	ns
inductancecentre of die ; $T_j = 25 \ ^{\circ}C$ from upper edge of drain mounting base to centre of die ; $T_j = 25 \ ^{\circ}C$ -2.5-nHLsinternal source inductancefrom source lead to source bond pad ; $T_j = 25 \ ^{\circ}C$ -7.5-nHSource-drain diodeVSource-drain voltageIs = 30 A; V_{GS} = 0 V; T_j = 25 \ ^{\circ}C; see Figure 15-0.851.2Vtrrreverse recovery timeIs = 20 A; dIs/dt = -100 A/\mus; V = 10 V/ V = 20 V/; T_r = 25 \ ^{\circ}C-80-ns	t <sub>f</sub>	fall time		-	110	-	ns
$to centre of die ; T_{j} = 25 \text{ °C}$ $L_{S} \qquad internal source inductance \qquad from source lead to source bond pad ; \qquad - 7.5  -  nH$ $T_{j} = 25 \text{ °C}$ Source-drain diode $V_{SD} \qquad source-drain voltage \qquad I_{S} = 30 \text{ A}; V_{GS} = 0 \text{ V}; T_{j} = 25 \text{ °C}; \qquad -  0.85  1.2 \text{ V}$ $t_{rr} \qquad reverse recovery time \qquad I_{S} = 20 \text{ A}; dI_{S}/dt = -100 \text{ A/}\mu\text{s}; \qquad -  80  -  n\text{s}$ $V_{V} = 10 \text{ V}; V_{V} = 20 \text{ V}; T_{V} = 25 \text{ °C}$	L <sub>D</sub>			-	4.5	-	nH
$\begin{array}{c cccc} inductance & T_{j} = 25 \ ^{\circ}C \\ \hline \begin{tabular}{lllllllllllllllllllllllllllllllllll$				-	2.5	-	nH
$V_{SD}$ source-drain voltage $I_S = 30 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ -         0.85         1.2         V $t_{rr}$ reverse recovery time $I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A}/\mu s;$ -         80         -         ns	L <sub>S</sub>		•	-	7.5	-	nH
see Figure 15 $t_{rr}$ reverse recovery time $I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A}/\mu s;$ - 80 - ns	Source-d	rain diode					
V. 10.V/.V. 20.V/.T 25.°C	$V_{SD}$	source-drain voltage		-	0.85	1.2	V
	t <sub>rr</sub>	reverse recovery time		-	80	-	ns
	Q <sub>r</sub>	recovered charge	$V_{GS}$ = -10 V; $V_{DS}$ = 30 V; $T_j$ = 25 °C	-	200	-	nC

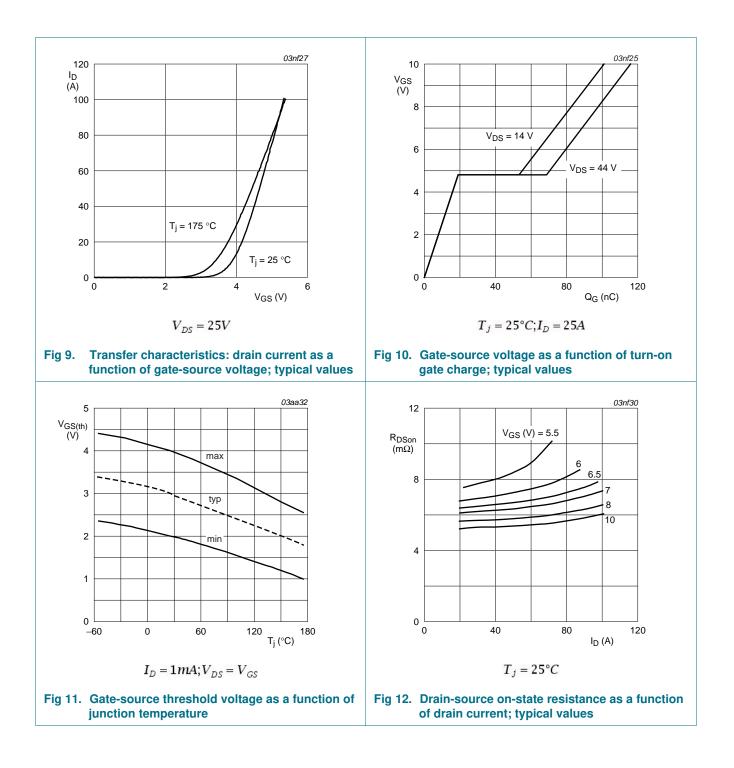
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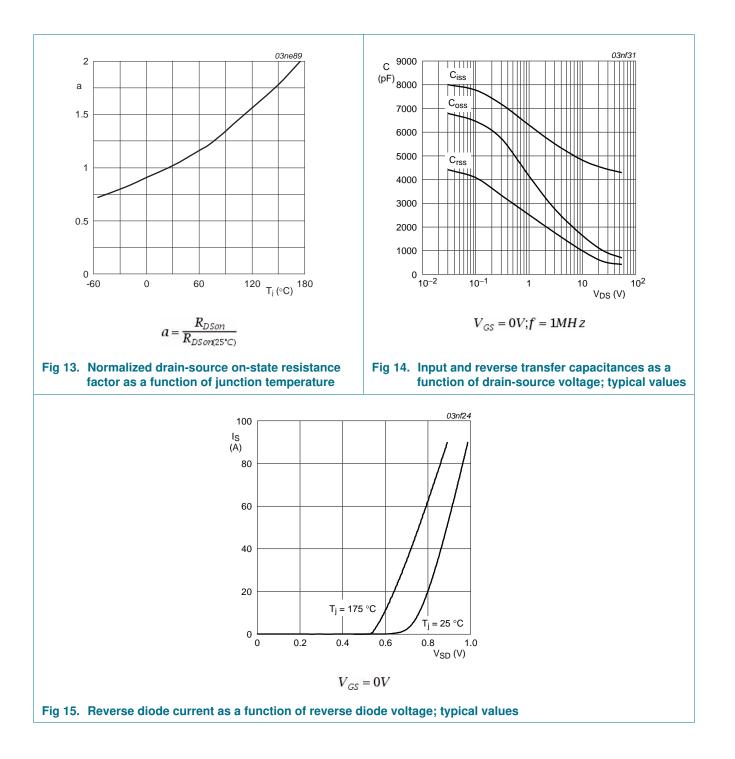
# BUK7606-55A

#### N-channel TrenchMOS standard level FET



# BUK7606-55A

#### N-channel TrenchMOS standard level FET



N-channel TrenchMOS standard level FET

### 7. Package outline

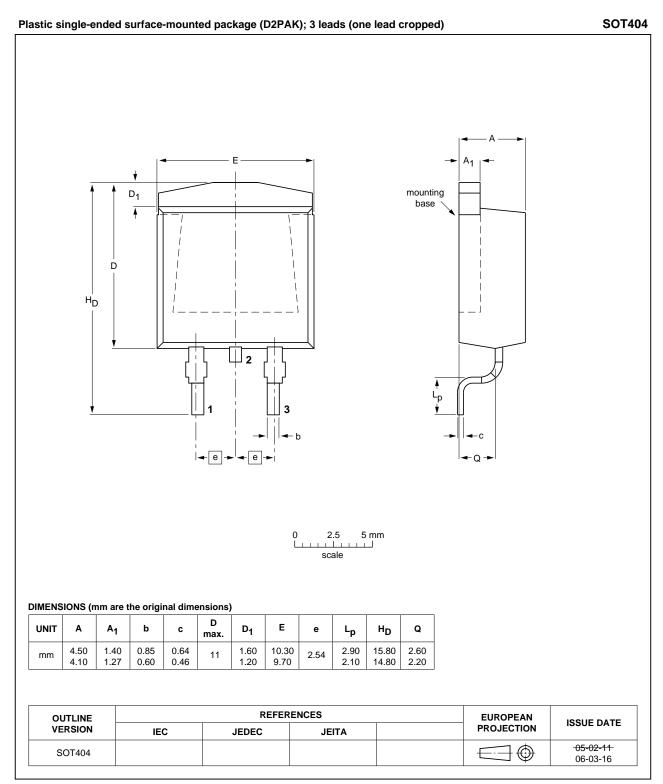


Fig 16. Package outline SOT404 (D2PAK)

All information provided in this document is subject to legal disclaimers.

BUK7606-55A

### N-channel TrenchMOS standard level FET

### 8. Revision history

Table 7. Revision hist	ory			
Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7606-55A v.3	20110201	Product data sheet	-	BUK7506_7606_55A v.2
Modifications:	guidelines of NX <ul> <li>Legal texts have</li> </ul>	s data sheet has been re P Semiconductors. been adapted to the new JK7606-55A separated fro	v company name wh	ere appropriate.
BUK7506_7606_55A v.2	20010703	Product Specification	-	-

#### N-channel TrenchMOS standard level FET

#### Legal information 9.

#### 9.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions'

The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product [3] status information is available on the Internet at URL http://www.nxp.com.

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Date of release: 1 February 2011 Document identifier: BUK7606-55A